

**Search Notes**

Application/Control No.

09/354,815

Examiner

Nhan T. Tran

Applicant(s)/Patent under  
Reexamination

TANAKA, TOSHIYUKI

Art Unit

2615

**SEARCHED**

| Class | Subclass | Date | Examiner |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE     | EXMR |
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| UPDATED EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)<br>test search - see search history<br>printout | 1/9/2006 | NT   |
| 348/362-367, 220.1-221.1, 227.1-229.1 (test search - see search history<br>printout)                           | 1/9/2006 | NT   |
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